

CLAIMS

1. An X-ray diffractometer, comprising
a sample stage for mounting a sample, the sample stage being
5 rotatable about an axis,
a double pinhole collimator for directing X-ray radiation to a sample on
the sample stage,
a detector for detecting X-rays diffracted by the sample, and
an analyser crystal arranged between the sample stage and the
10 detector to direct X-rays diffracted by the sample onto the detector,
wherein the analyser crystal and detector are rotatable about an axis
that is coaxial with the axis of rotation of the sample stage.
2. An X-ray diffractometer according to claim 1 wherein the size of
15 the pinhole of the double pinhole collimator nearest the sample stage is
adjustable for providing an X-ray spot on the sample of variable size.
3. An X-ray diffractometer according to claim 1 wherein a slit is
arranged between the sample stage and the detector.
- 20 4. An X-ray diffractometer according to claim 3 wherein the slit is
arranged in front of the detector.
5. An X-ray diffractometer according to claim 1 and further
25 comprising a drive for rotating the sample stage and the detector and analyser
crystal with a ratio of rotation angles of substantially 1:2.